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EUROPEAN PATENT APPLICATION

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(54) Isotopic reference material

(57) This application relates to a reference material for the calibration of a mass spectrometer for isotopic analysis, the reference material including

a filament comprising one or more metals (X) selected from W, Re, Rh, Ir, Pd and Pt and alloys thereof having melting points greater than approximately 1800°C and vapour pressures lower than approximately 10⁻⁶ Torr at 2000°C,

the filament having a coating on at least a portion

thereof of an intermetallic compound comprising one or more metals (Y) selected from W, Re, Rh, Ir, Pd and Pt and alloys thereof having melting points greater than approximately 1800°C and vapour pressures lower than 10⁻⁶ Torr at approximately 2000°C and one or more metals (Z) selected from the lanthanides and the actinides.



EUROPEAN SEARCH REPORT

Application Number EP 00 30 4683

	DOCUMENTS CONSIDEI	RED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages		Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.CI.7)	
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EUROPEAN SEARCH REPORT

Application Number EP 00 30 4683

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